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Bib Data Sheet

CONFIRMATION NO. 3931

Yuan-Ku Lan, Panchiao City, TAIWAN; *** CONTINUING DATA **********************************	SERIAL NUMBE 10/086,928	R	FILING DATE 02/28/2002 RULE	C	382	GROUP ART UNIT 2621		ATTORNEY DOCKET NO. B-4514 619559-4			
*** CONTINUING DATA **********************************	APPLICANTS										
TAIWAN 90121880 09/04/2001 IF REQUIRED, FOREIGN FILING LICENSE GRANTED **03/22/2002 Foreign Priority claimed	Yuan-Ku La	n, Pa	anchiao City, TAIWAN;								
TAIWAN 90121880 09/04/2001 IF REQUIRED, FOREIGN FILING LICENSE GRANTED *** 03/22/2002 Foreign Priority claimed	** CONTINUING DATA **********************************										
FILING FEE RECEIVED 740 Foreign Priority claimed	** FOREIGN APPLICATIONS ************************************										
35 USC 119 (a-d) conditions	IF REQUIRED, FOREIGN FILING LICENSE GRANTED ** 03/22/2002										
Richard P. Berg, Esq. c/o LADAS & PARRY 5670 Wilshire Boulevard, Suite 2100 Los Angeles ,CA 90036-5679 TITLE Method of checking overlap accuracy of patterns on four stacked semiconductor layers FILING FEE RECEIVED 740 FEES: Authority has been given in Paper No to charge/credit DEPOSIT ACCOUNT No for following: All Fees 1.16 Fees (Filing) 1.17 Fees (Processing Ext. of time) 1.18 Fees (Issue) Other	met Verified and Acknowledged	tions	yes no Met aft		COUNTRY	Y DRAWING CL		CLAI	IMS CLAIMS		
c/o LADAS & PARRY 5670 Wilshire Boulevard, Suite 2100 Los Angeles ,CA 90036-5679 TITLE Method of checking overlap accuracy of patterns on four stacked semiconductor layers FILING FEE RECEIVED 740 FEES: Authority has been given in Paper to charge/credit DEPOSIT ACCOUNT No for following: All Fees 1.16 Fees (Filing) 1.17 Fees (Processing Ext. of time) 1.18 Fees (Issue) 1.18 Fees (Issu	ADDRESS										
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